# EE 330 Lecture 39

### **Digital Circuits**

Sizing of Devices for Logic Circuits (preliminary)
Ratio Logic
Other MOS Logic Families
Propagation Delay – basic characterization

#### Fall 2024 Exam Schedule

Exam 1 Friday Sept 27

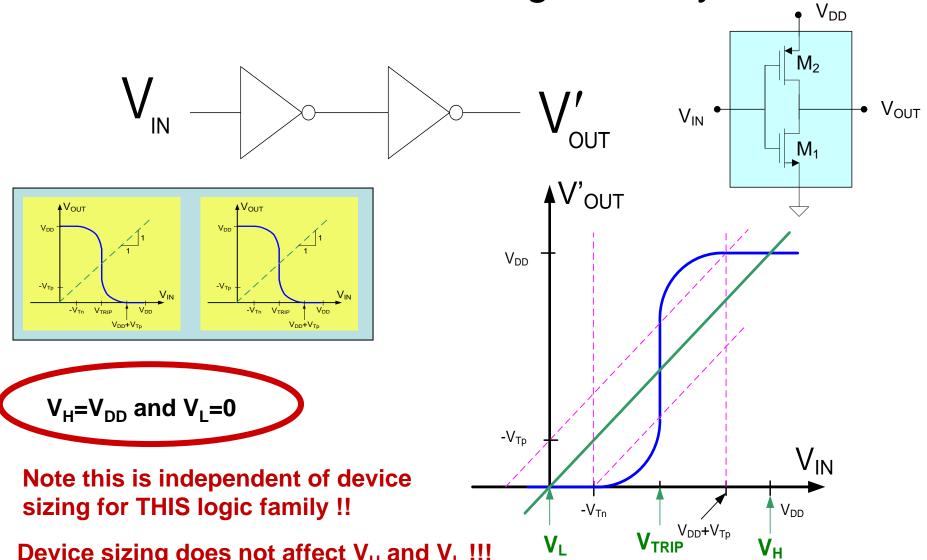
Exam 2 Friday October 25

Exam 3 Friday Nov 22

Final Exam Monday Dec 16 12:00 - 2:00

**PM** 

Review from last lecture
Inverter Transfer Characteristics of Inverter Pair for THIS Logic Family

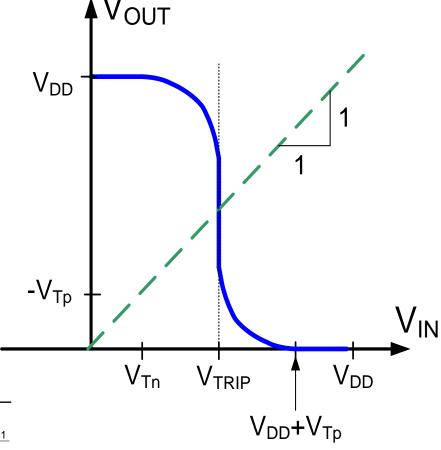


Device sizing does not affect V<sub>H</sub> and V<sub>I</sub> !!!

#### Review from last lecture

#### Transfer characteristics of the static CMOS inverter

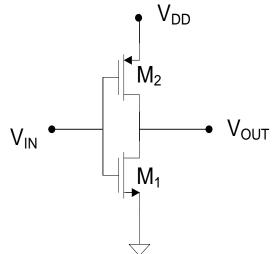
(Neglect λ effects)



#### From Case 3 analysis:

$$V_{_{IN}} = \frac{\left(V_{_{Tn}}\right) + \left(V_{_{DD}} + V_{_{Tp}}\right) \sqrt{\frac{\mu_{_{p}}}{\mu_{_{n}}}} \frac{W_{_{2}}}{W_{_{1}}} \frac{L_{_{1}}}{L_{_{2}}}}{1 + \sqrt{\frac{\mu_{_{p}}}{\mu_{_{n}}} \frac{W_{_{2}}}{W_{_{1}}} \frac{L_{_{1}}}{L_{_{2}}}}}$$

# Sizing of the Basic CMOS Inverter



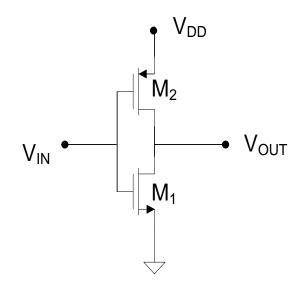
Most logic families require using the device sizing variables to determine acceptable  $V_H$  and  $V_L$  values

The characteristic that device sizes do not need to be used to establish  $V_H$  and  $V_L$  logic levels is a major advantage of this type of logic !!

How should  $M_1$  and  $M_2$  be sized?

How many degrees of freedom are there in the design of the inverter?

## How should M<sub>1</sub> and M<sub>2</sub> be sized?



How many degrees of freedom are there in the design of the inverter?

$$\{ W_1, W_2, L_1, L_2 \}$$

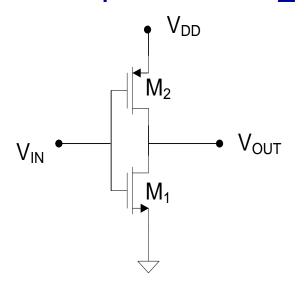
4 degrees of freedom

But in basic device model and in  $\underline{most}$  performance metrics,  $W_1/L_1$  and  $W_2/L_2$  appear as ratios

 $\{ W_1/L_1, W_2/L_2 \}$ 

effectively 2 degrees of freedom

# How should M₁ and M₂ be sized?



$$\{W_1, W_2, L_1, L_2\}$$
 4 degrees of freedom Usually pick  $L_1 = L_2 = L_{min}$ 

That leaves

 $\{ W_1, W_2 \}$ 

effectively 2 degrees of freedom

How are W<sub>1</sub> and W<sub>2</sub> chosen?

Depends upon what performance parameters are most important for a given application!

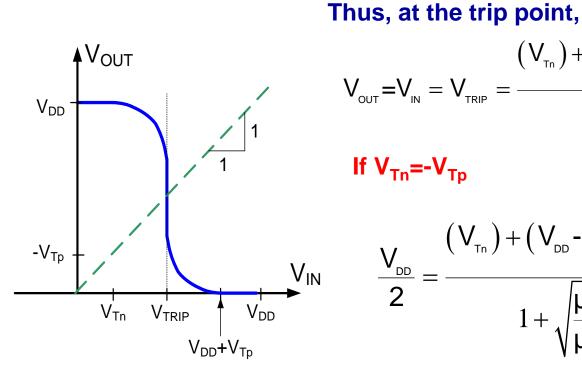
# How should M₁ and M₂ be sized?

Pick L<sub>1</sub>=L<sub>2</sub>=L<sub>min</sub>

#### **One** popular sizing strategy:

- Pick  $W_1=W_{MIN}$  to minimize area of  $M_1$
- 2. Pick  $W_2$  to set trip-point at  $V_{DD}/2$





$$V_{\text{OUT}} = V_{\text{IN}} = V_{\text{TRIP}} = \frac{\left(V_{\text{Tn}}\right) + \left(V_{\text{DD}} + V_{\text{Tp}}\right) \sqrt{\frac{\mu_{\text{p}}}{\mu_{\text{n}}} \frac{W_{\text{2}}}{W_{\text{1}}}}}{\sqrt{\frac{\mu_{\text{p}}}{\mu_{\text{n}}} \frac{W_{\text{2}}}{W_{\text{1}}}}}$$

$$\frac{V_{_{DD}}}{2} = \frac{\left(V_{_{Tn}}\right) + \left(V_{_{DD}} - V_{_{Tn}}\right) \sqrt{\frac{\mu_{_{p}}}{\mu_{_{n}}} \frac{W_{_{2}}}{W_{_{1}}}}}{1 + \sqrt{\frac{\mu_{_{p}}}{\mu_{_{n}}} \frac{W_{_{2}}}{W_{_{1}}}}}$$

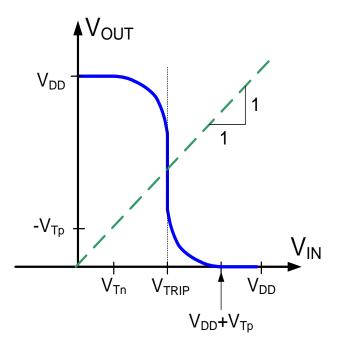
# How should M₁ and M₂ be sized?

#### **One** popular sizing strategy:

- Pick W<sub>1</sub>=W<sub>MIN</sub> to minimize area of M<sub>1</sub>
- Pick W<sub>2</sub> to set trip-point at V<sub>DD</sub>/2

Observe Case 3 provides expression for V<sub>TRIP</sub>

(solution continued)



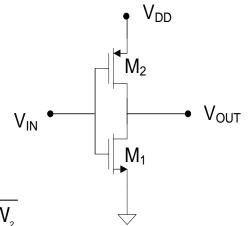
$$\frac{V_{_{DD}}}{2} = \frac{\left(V_{_{Tn}}\right) + \left(V_{_{DD}} \text{-} V_{_{Tn}}\right) \sqrt{\frac{\mu_{_{p}}}{\mu_{_{n}}} \frac{W_{_{2}}}{W_{_{1}}}}}{1 + \sqrt{\frac{\mu_{_{p}}}{\mu_{_{n}}} \frac{W_{_{2}}}{W_{_{1}}}}}$$

solving for  $\sqrt{\frac{\mu_p}{\mu}\frac{W_2}{W}}$ we obtain

$$\sqrt{\frac{\mu_{_{D}}}{\mu_{_{n}}}} \frac{W_{_{2}}}{W_{_{1}}} = \frac{V_{_{Tn}} - \frac{V_{_{DD}}}{2}}{-\frac{V_{_{DD}}}{2} + V_{_{Tn}}} = 1$$
This is independent of  $V_{Tn}$  and  $V_{DD}!$ 

thus

$$\frac{W_2}{W_1} = \frac{\mu_n}{\mu_p} \qquad \Longrightarrow W_2 = \frac{\mu_n}{\mu_p} W_{MIN} \simeq 3W_{MIN}$$

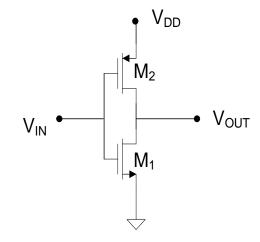


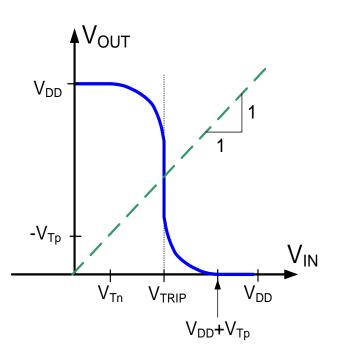
# How should M<sub>1</sub> and M<sub>2</sub> be sized?

#### One popular sizing strategy:

- 1. Pick  $W_1=W_{MIN}$  to minimize area of  $M_1$
- 2. Pick  $W_2$  to set trip-point at  $V_{DD}/2$

Observe Case 3 provides expression for  $V_{TRIP}$ 





Summary: 
$$V_{TRIP} = \frac{V_{DD}}{2}$$
 sizing strategy

$$L_1=L_2=L_{min}$$

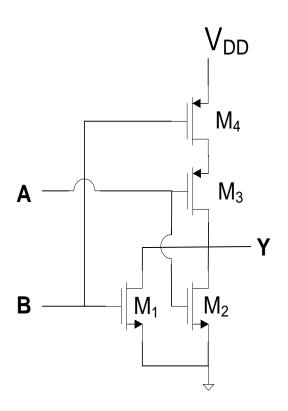
$$W_1 = W_{MIN}$$

$$W_2 = \frac{\mu_n}{\mu_n} W_{MIN} \simeq 3W_{MIN}$$

(dependent upon assumption  $V_{Tp} = -V_{Tn}$ )

Other sizing strategies will be discussed later!

# Extension of Basic CMOS Inverter to Multiple-Input Gates



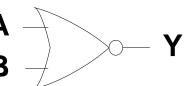
Α	В	Υ
0	0	1
0	~	0
1	0	0
1	1	0

Truth Table

Performs as a 2-input NOR Gate

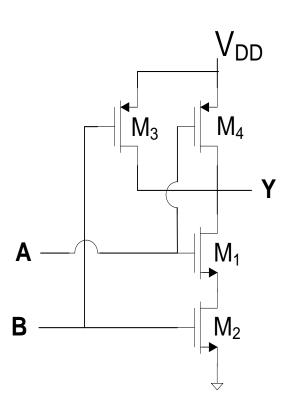
Can be easily extended to an n-input NOR Gate

 $V_{H}=V_{DD}$  and  $V_{L}=0$  (inherited from inverter analysis)



analysis not shown here but straightforward and consistent with claim that performance of gates in logic family determined by those of basic inverter

# Extension of Basic CMOS Inverter to Multiple-Input Gates



Α	В	Υ
0	0	1
0	1	1
1	0	1
1	1	0

Truth Table

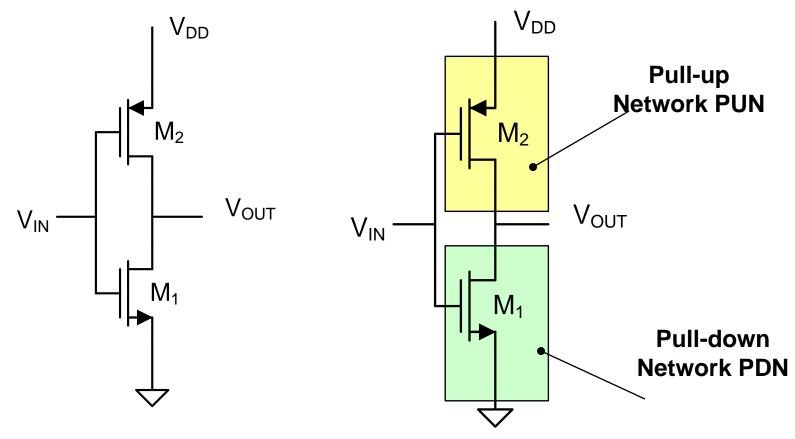
**Performs as a 2-input NAND Gate** 

Can be easily extended to an n-input NAND Gate

B - Y

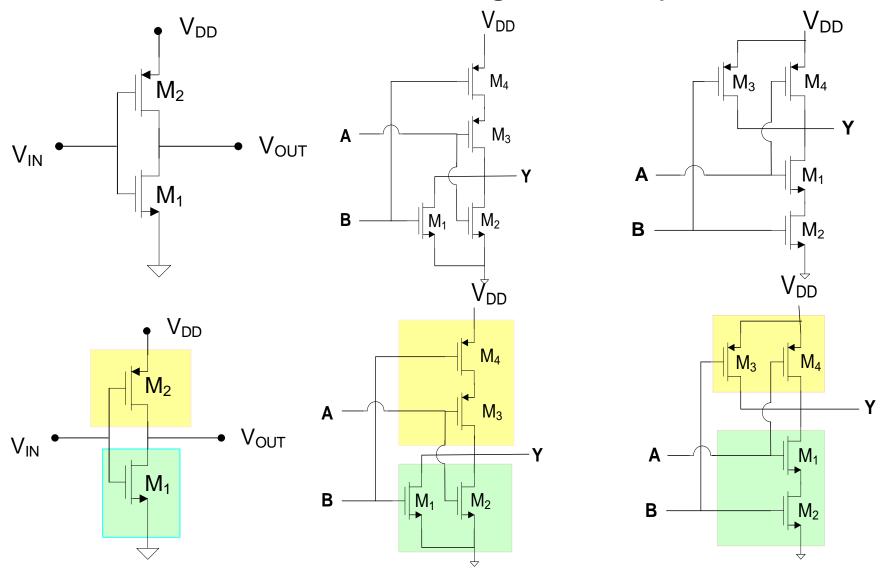
 $V_H = V_{DD}$  and  $V_L = 0$  (inherited from inverter analysis)

# Static CMOS Logic Family



- Observe PUN is p-channel, PDN is n-channel
- Claim: If PUN comprised of p-channel, PDN comprised of n-channels and one and only one is conducting, then  $V_H = V_{DD}$  and  $V_L = 0$
- inherited from inverter analysis

### Static CMOS Logic Family



n-channel PDN and p-channel PUN  $V_H=V_{DD}$ ,  $V_L=0V$  (same as for inverter!)

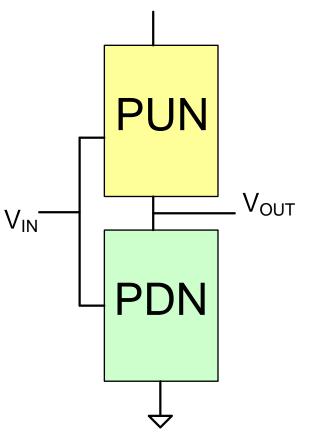
# Digital Circuit Design

- Hierarchical Design
- Basic Logic Gates
- Properties of Logic Families
- Characterization of CMOS Inverter
- Static CMOS Logic Gates
  - Ratio Logic
  - Propagation Delay
  - Simple analytical models
    - FI/OD
    - Logical Effort
    - Elmore Delay
- Sizing of Gates
  - The Reference Inverter

- Propagation Delay with Multiple Levels of Logic
- Optimal driving of Large Capacitive Loads
- Power Dissipation in Logic Circuits
- Other Logic Styles
- Array Logic
- Ring Oscillators

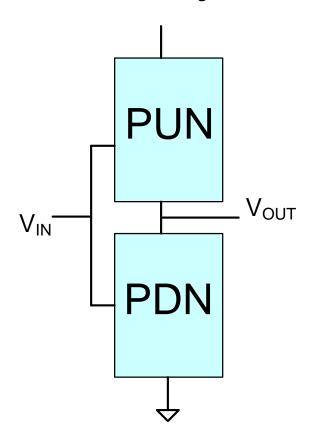
done partial

# General Logic Family



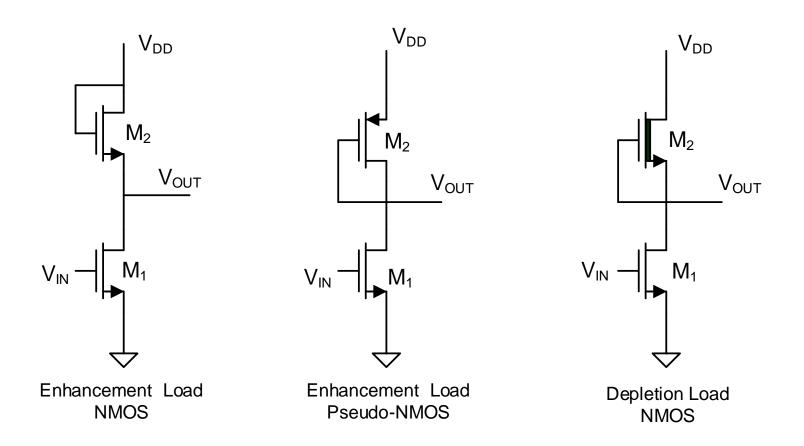
**Compound Gate in CMOS Process** 

p-channel PUN n-channel PDN  $V_H=V_{DD},\ V_L=0V$  (same as for inverter!)

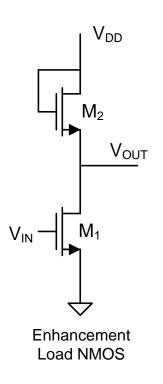


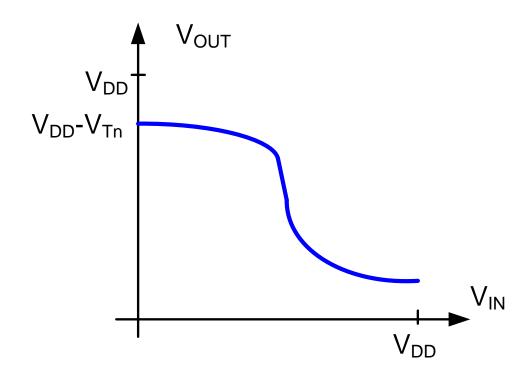
**Arbitrary PUN** and PDN

(Arbitrary PUN and PDN)

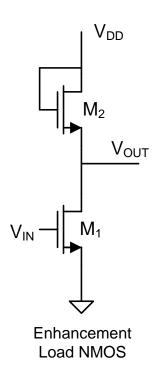


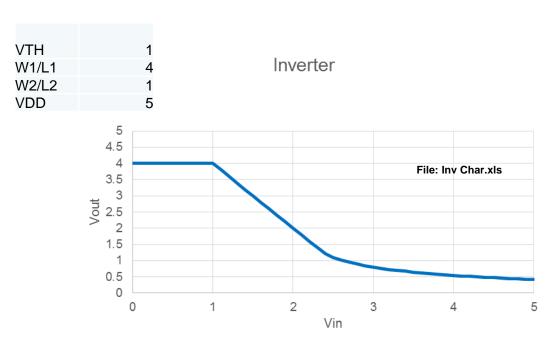
These are termed "ratio logic" gates

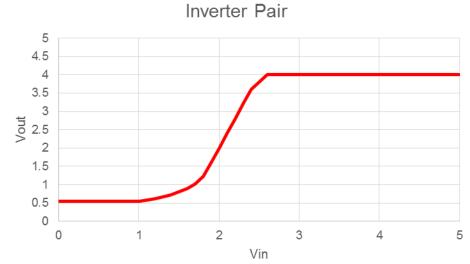




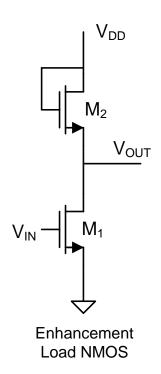
## NMOS example







### NMOS example

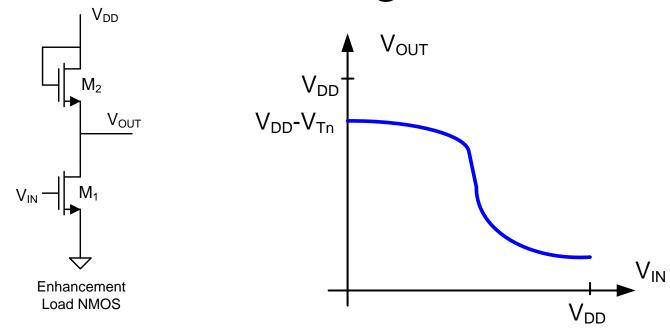


VTH	1
W1/L1	4
W2/L2	1
VDD	5





```
V_H=4V
V_L=0.55V
V_{TRIP}=2V
```



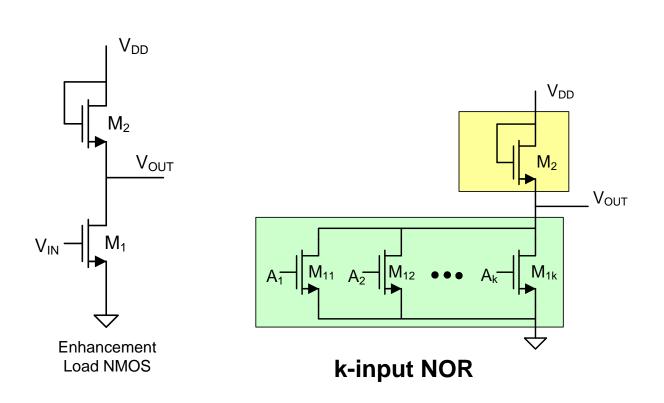
- High and low swings are reduced
- Response time is slow on LH output transitions
- Static Power Dissipation Large when V<sub>OUT</sub> is low (will sl
- Very economical process



- Termed "ratio logic" (because logic values dependent on device W/L ratios USE UP DOF!)
- May not work for some device sizes
- Compact layout (no wells!)



- Can use very low cost process
- Available to use in standard CMOS process

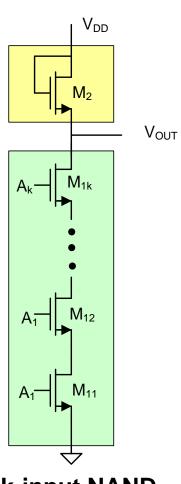


 Multiple-input gates require single transistor for each additional input

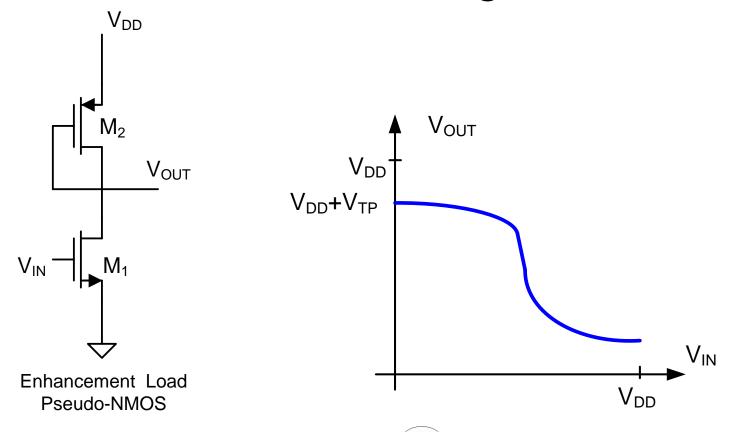


Still useful if many inputs are required
 (will be shown that static power does not increase with k)



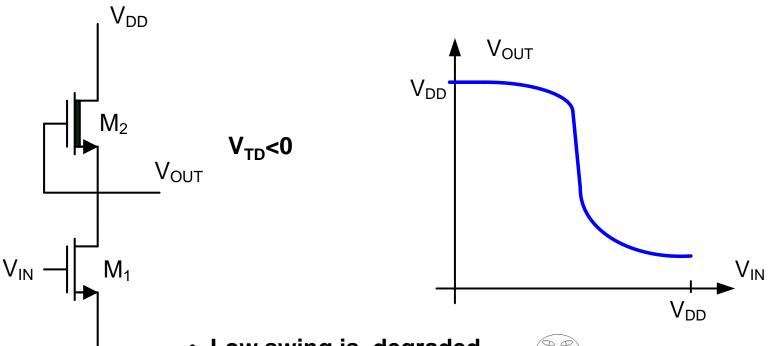


k-input NAND



- High and low swings are reduced
- Response time is slow on LH output transitions
- Static Power Dissipation Large when V<sub>OUT</sub> is low
- Multiple-input gates require single transistor for each additional input
- Termed "ratio" logic
- Available to use in standard CMOS process





Depletion

Load NMOS

Low swing is degraded

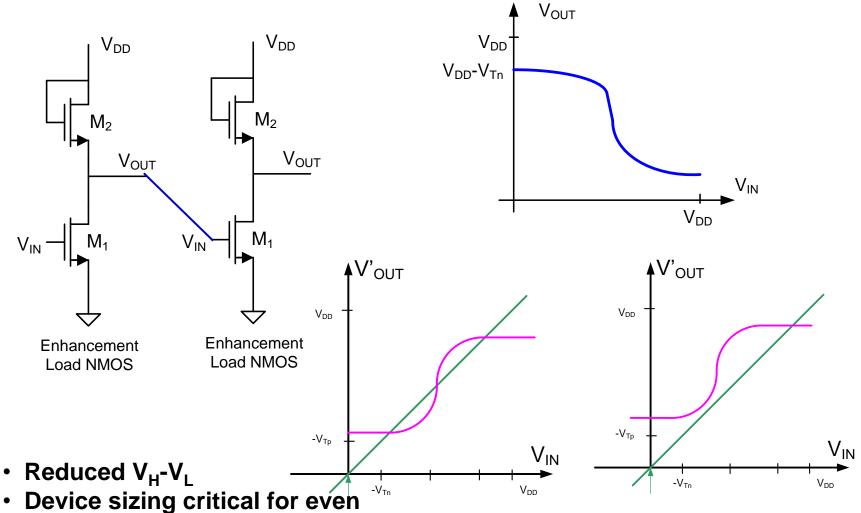




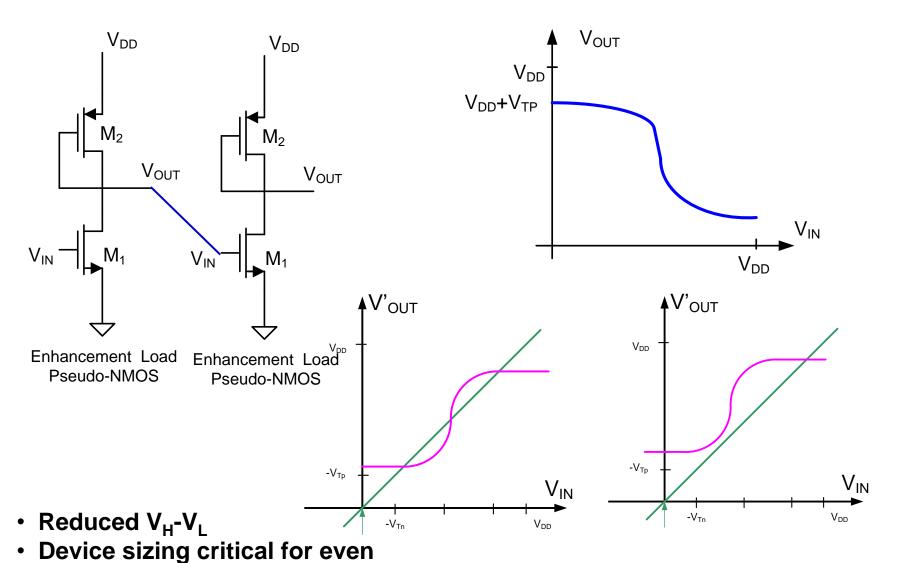


- Better than Enhancement Load NMOS
- Termed "ratio" logic
- Compact layout (no wells!)
- Slow on L-H output transitions (but not as slow as previous ic)
- Dominant MOS logic until about 1985
- Depletion device not available in most processes today

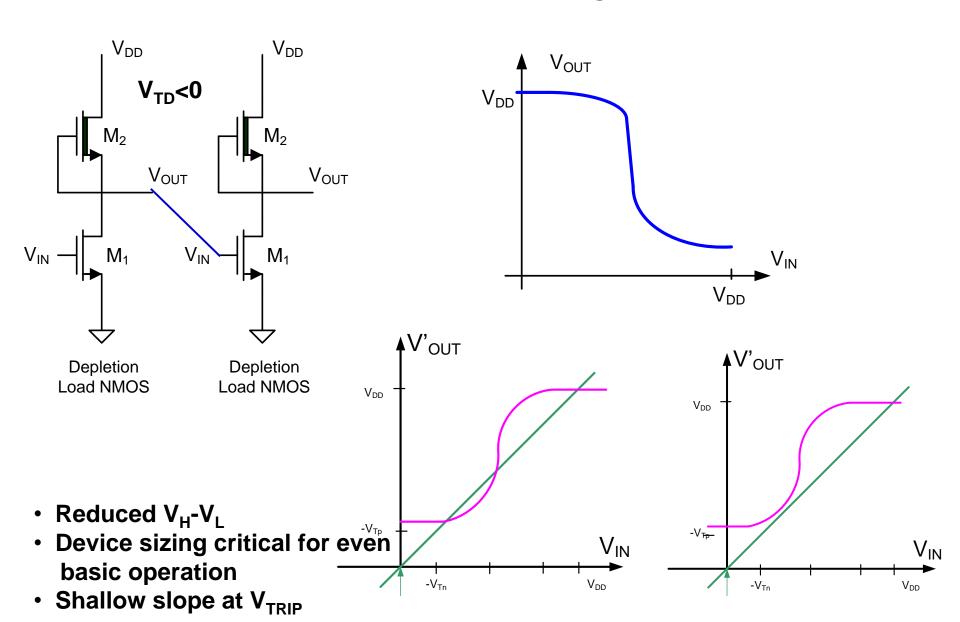




- Device sizing critical for ever basic operation
- Shallow slope at V<sub>TRIP</sub>



basic operation (DOF)Shallow slope at V<sub>TRIP</sub>



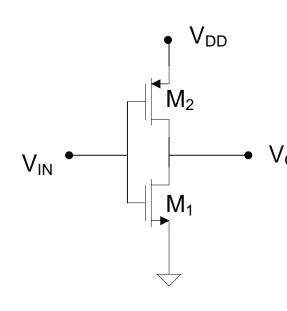
# Digital Circuit Design

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done partial

### Static Power Dissipation in Static CMOS Family

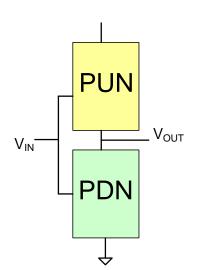


When  $V_{IN}$  is Low and  $V_{OUT}$  is High,  $M_1$  is off and  $I_{D1}=0$ 

When  $V_{IN}$  is High and  $V_{OUT}$  is Low,  $M_2$  is off and  $I_{D2}=0$ 

Thus, P<sub>STATIC</sub>=0

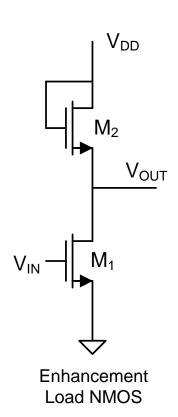
This is a key property of the static CMOS Logic Family → the major reason Static CMOS Logic is so dominant



It can be shown that this zero static power dissipation property can be preserved if the PUN is comprised of p-channel devices, the PDN is comprised of n-channel devices and they are never both driven into the conducting states at the same time

# Static Power Dissipation in Ratio Logic Families

#### **Example:**



Assume  $V_{DD}=5V$  $V_{Tn}=1V$ ,  $\mu C_{OX}=10^{-4}A/V^2$ ,  $W_1/L_1=1$  and  $M_2$  sized so that  $V_1$  is close to  $V_{Tn}$ 

#### **Observe:**

$$V_H = V_{DD} - V_{Tn}$$

If 
$$V_{IN}=V_H$$
,  $V_{OUT}=V_L$  so

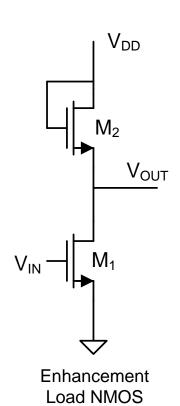
$$I_{D1} = \frac{\mu C_{OX} W_1}{L_1} \left( V_{GS1} - V_{Tn} - \frac{V_{DS1}}{2} \right) V_{DS1}$$

$$I_{D1} = 10^{-4} \left( 5 - 1 - 1 - \frac{1}{2} \right) \cdot 1 = 0.25 \text{mA}$$

$$P_1 = (5V)(0.25mA) = 1.25mW$$

# Static Power Dissipation in Ratio Logic Families

#### **Example:**



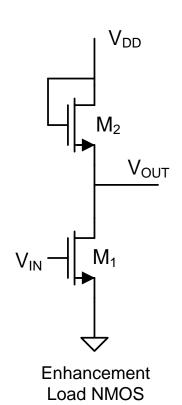
Assume  $V_{DD}$ =5V  $V_{T}$ =1V,  $\mu C_{OX}$  =10<sup>-4</sup>A/V<sup>2</sup>,  $W_{1}/L_{1}$ =1 and  $M_{2}$  sized so that  $V_{L}$  is close to  $V_{Tn}$ 

 $P_L = (5V)(0.25mA) = 1.25mW$ 

If a circuit has 100,000 gates and half of them are in the  $V_{OUT}=V_L$  state, the static power dissipation will be

# Static Power Dissipation in Ratio Logic Families

#### **Example:**



Assume  $V_{DD}$ =5V  $V_{T}$ =1V,  $\mu C_{OX}$  =10<sup>-4</sup>A/V<sup>2</sup>,  $W_{1}/L_{1}$ =1 and  $M_{2}$  sized so that  $V_{1}$  is close to  $V_{Tn}$ 

$$P_L = (5V)(0.25mA) = 1.25mW$$

If a circuit has 100,000 gates and half of them are in the  $V_{OUT}=V_L$  state, the static power dissipation will be

$$P_{STATIC} = \frac{1}{2}10^5 \bullet 1.25 mW = 62.5W$$

This power dissipation is way too high and would be even larger in circuits with 100 million or more gates – the level of integration common in SoC circuits today

# Digital Circuit Design

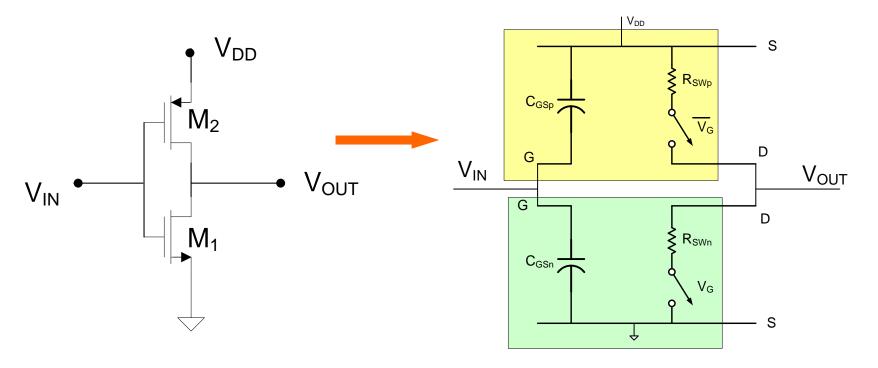
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done partial

### Propagation Delay in Static CMOS Family

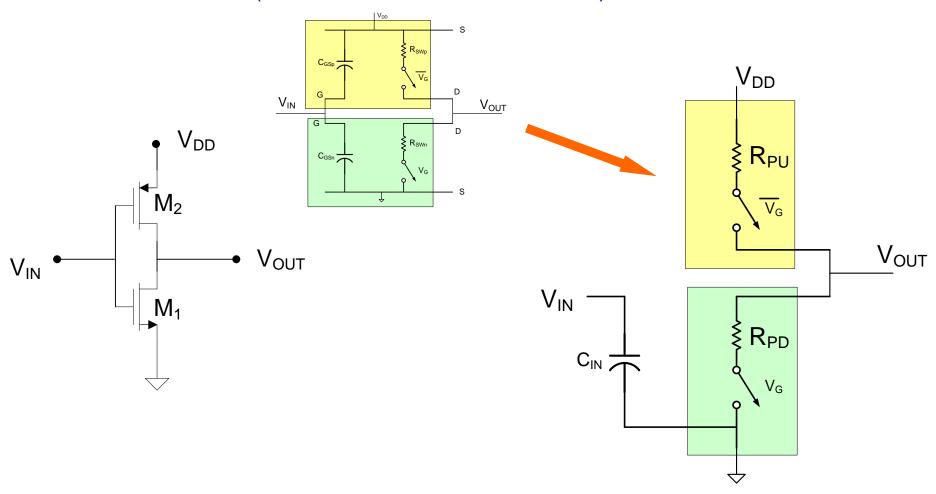
(Review from earlier discussions)



Switch-level model of Static CMOS inverter (neglecting diffusion parasitics)

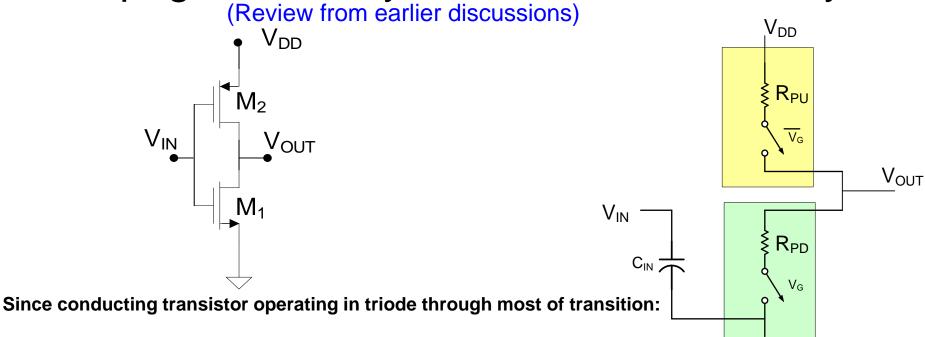
#### Propagation Delay in Static CMOS Family

(Review from earlier discussions)



Switch-level model of Static CMOS inverter (neglecting diffusion parasitics)

### Propagation Delay in Static CMOS Family



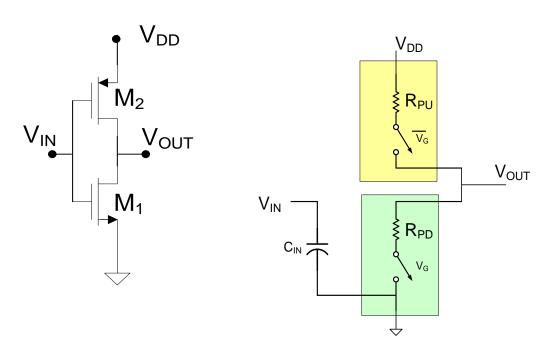
$$\boldsymbol{I}_{\text{D}} \cong \frac{\mu \boldsymbol{C}_{\text{OX}} \boldsymbol{W}}{L} \! \left( \boldsymbol{V}_{\text{GS}} - \boldsymbol{V}_{\text{T}} - \frac{\boldsymbol{V}_{\text{DS}}}{2} \right) \! \boldsymbol{V}_{\text{DS}} \cong \frac{\mu \boldsymbol{C}_{\text{OX}} \boldsymbol{W}}{L} \! \left( \boldsymbol{V}_{\text{GS}} - \boldsymbol{V}_{\text{T}} \right) \! \boldsymbol{V}_{\text{DS}}$$

$$R_{PD} = \frac{V_{DS}}{I_{D}} = \frac{L_{1}}{\mu_{n}C_{OX}W_{1}(V_{DD} - V_{Tn})}$$

$$R_{PU} = \frac{V_{DS}}{I_{D}} = \frac{L_{2}}{\mu_{p}C_{OX}W_{2}(V_{DD} + V_{Tp})}$$

$$\boldsymbol{C}_{\text{IN}} = \boldsymbol{C}_{\text{OX}} \big( \boldsymbol{W}_{\!1} \boldsymbol{L}_{\!1} + \boldsymbol{W}_{\!2} \boldsymbol{L}_{\!2} \big)$$

(Review from earlier discussions)



$$\boldsymbol{R}_{PD} = \frac{\boldsymbol{L}_{1}}{\boldsymbol{\mu}_{n}\boldsymbol{C}_{o\boldsymbol{X}}\boldsymbol{W}_{1}\!\left(\boldsymbol{V}_{DD} - \boldsymbol{V}_{Tn}\right)}$$

$$\boldsymbol{R}_{\text{PU}} = \frac{\boldsymbol{L}_{\text{2}}}{\boldsymbol{\mu}_{\text{p}}\boldsymbol{C}_{\text{OX}}\boldsymbol{W}_{\text{2}}\!\left(\boldsymbol{V}_{\text{DD}} + \boldsymbol{V}_{\text{Tp}}\right)}$$

$$\mathbf{C}_{\mathsf{IN}} = \mathbf{C}_{\mathsf{OX}} \big( \mathbf{W}_{\mathsf{1}} \mathbf{L}_{\mathsf{1}} + \mathbf{W}_{\mathsf{2}} \mathbf{L}_{\mathsf{2}} \big)$$

#### Example: Minimum-sized M<sub>1</sub> and M<sub>2</sub>

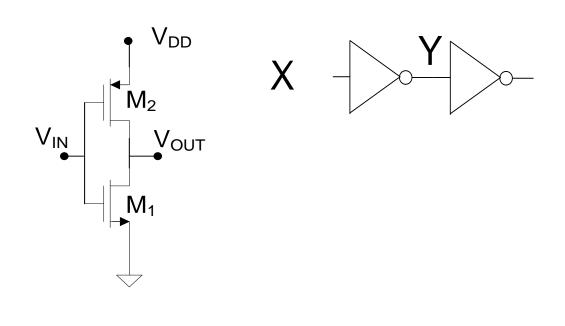
 $\begin{array}{l} \text{If } u_{n}C_{OX} = 100 \mu \text{AV}^{-2}, \ C_{OX} = 4 \text{ fF}\mu^{-2}, \ V_{Tn} = V_{DD}/5, \ V_{TP} = -V_{DD}/5, \ \mu_{n}/\mu_{p} = 3, \ L_{1} = W_{1} = L_{MIN}, \ L_{2} = W_{2} = L_{MIN}, \ L_{MIN} = 0.5 \mu \text{ and } V_{DD} = 5 V \end{array} \\ \begin{array}{l} \text{(Note: This $C_{OX}$ is somewhat larger than that in the 0.5u ON process)} \end{array}$ 

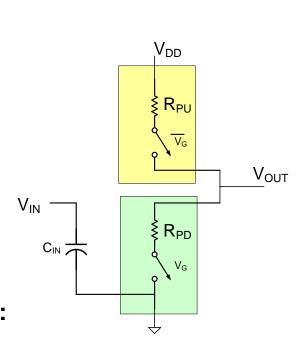
$$R_{PD} = \frac{1}{10^{-4} \cdot 0.8 V_{DD}} = 2.5 K\Omega$$

$$C_{IN} = 4 \cdot 10^{-15} \cdot 2 L_{MIN}^2 = 2 fF$$

$$R_{PU} = \frac{1}{10^{-4} \cdot \frac{1}{2} \cdot 0.8 V_{DD}} = 7.5 K\Omega$$

(Review from earlier discussions)





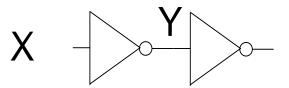
#### In typical process with Minimum-sized M<sub>1</sub> and M<sub>2</sub>:

$$R_{PD} \cong 2.5 K\Omega$$

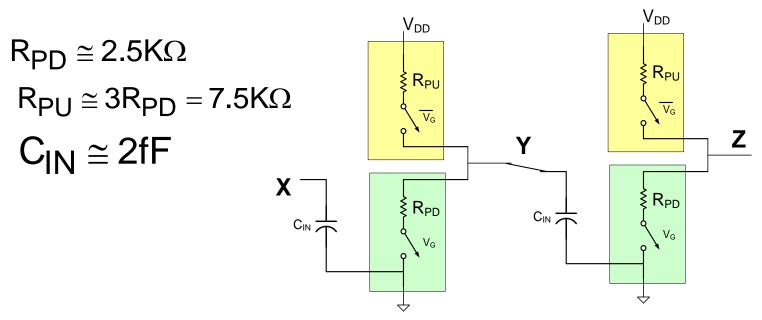
$$R_{PU} \cong 3R_{PD} = 7.5K\Omega$$
  
 $C_{IN} \cong 2fF$ 

$$C_{IN} \cong 2fF$$

(Review from earlier discussions)



In typical process with Minimum-sized M<sub>1</sub> and M<sub>2</sub>:



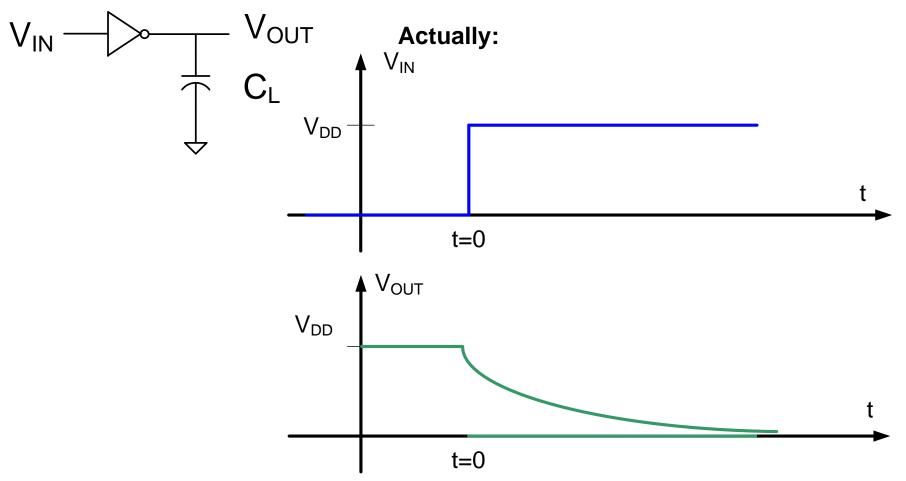
How long does it take for a signal to propagate from x to y?

(Review from earlier discussions)

**Consider:** For HL output transition, C<sub>L</sub> charged to V<sub>DD</sub> Ideally:  $V_{\text{DD}}$ t=0  $V_{OUT}$  $V_{\text{DD}}$ t=0

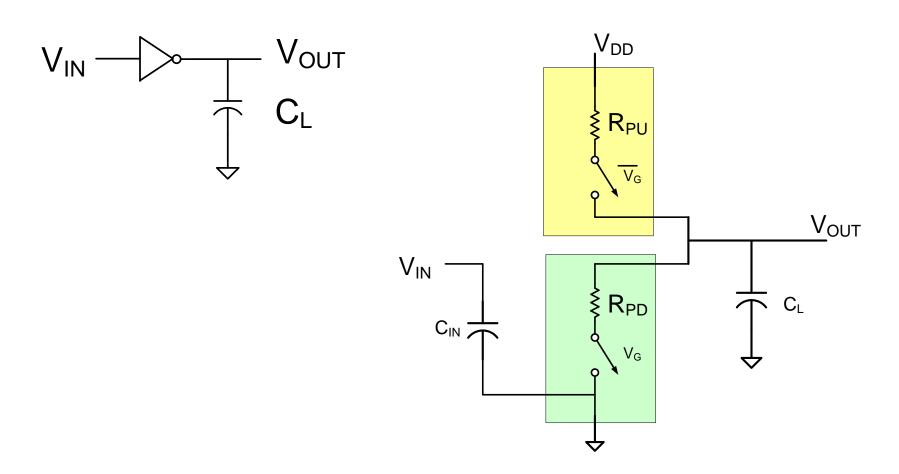
(Review from earlier discussions)

For HL output transition, C<sub>L</sub> charged to V<sub>DD</sub>



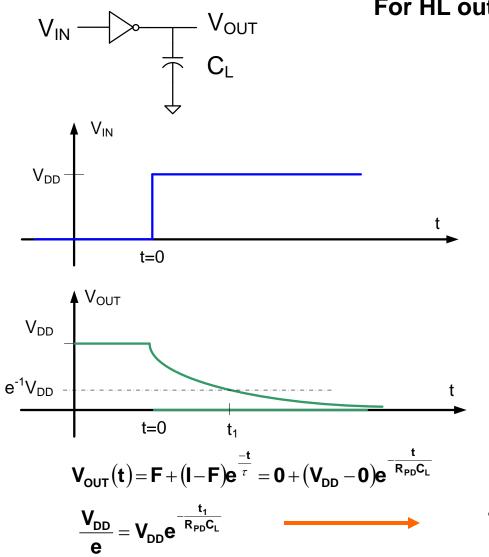
What is the transition time  $t_{HL}$ ?

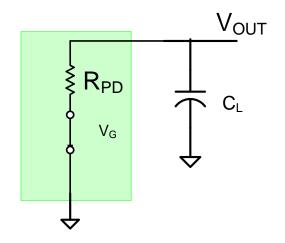
(Review from earlier discussions)



(Review from earlier discussions)



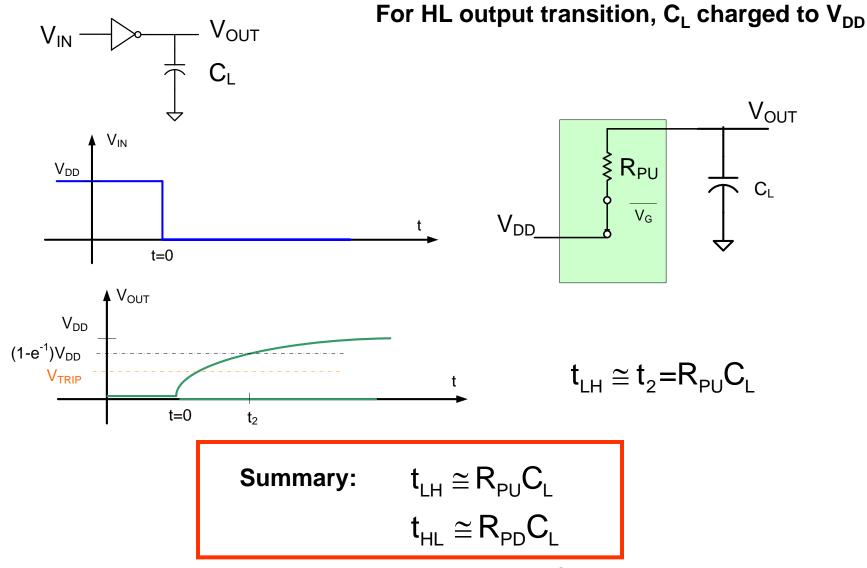




$$\mathbf{t}_1 = \mathbf{R}_{PD} \mathbf{C}_{L}$$

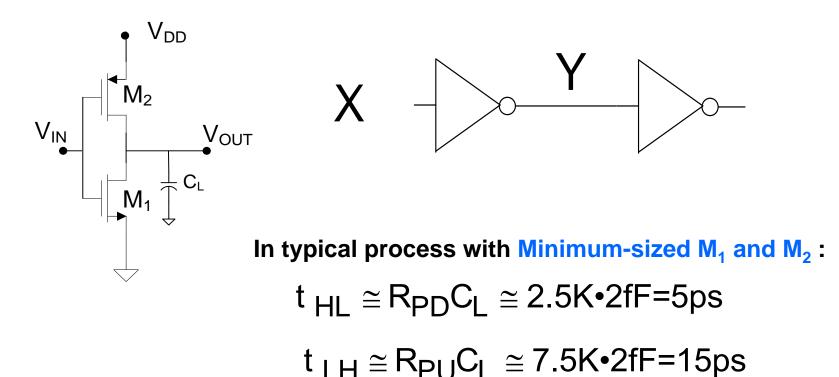
If  $V_{TRIP}$  is close to  $V_{DD}/2$ ,  $t_{HL}$  is close to  $t_1$ 

(Review from earlier discussions)



For  $V_{TRIP}$  close to  $V_{DD}/2$ 

(Review from earlier discussions)



LH = 1.600L = 1.617 211 1.666

(Note: This  $C_{\text{OX}}$  is somewhat larger than that in the 0.5u ON process)

Note: LH transition is much slower than HL transition

Defn: The Propagation Delay of a gate is defined to be the sum of  $t_{HL}$  and  $t_{LH}$ , that is,  $t_{PROP} = t_{HL} + t_{LH}$ 

$$t_{PROP} = t_{HL} + t_{LH} \cong C_L (R_{PU} + R_{PD})$$

Propagation delay represents a fundamental limit on the speed a gate can be clocked at

For basic two-inverter cascade <u>with minimum-sized devices</u> in static 0.5um CMOS logic driving an identical device

X 
$$t_{PROP} = t_{HL} + t_{LH} \cong 20p \text{ sec}$$

$$t_{PROP} = t_{HL} + t_{LH} \cong C_L (R_{PU} + R_{PD})$$

$$R_{PD} = \frac{L_1}{\mu_n C_{ox} W_1 (V_{DD} - V_{Tn})} \qquad R_{PU} = \frac{L_2}{\mu_p C_{ox} W_2 (V_{DD} + V_{Tp})} \qquad \qquad C_{IN} = C_{ox} \big( W_1 L_1 + W_2 L_2 \big)$$

If  $V_{Tn} = -V_{Tp} = V_{T}$  and if  $C_L = C_{IN}$ 

$$t_{PROP} = C_{OX}(W_{1}L_{1} + W_{2}L_{2}) \left( \frac{L_{1}}{\mu_{n}C_{OX}W_{1}(V_{DD} - V_{T})} + \frac{L_{2}}{\mu_{p}C_{OX}W_{2}(V_{DD} - V_{T})} \right)$$

If 
$$L_{2} = L_{1} = L_{\min}$$
,  $\mu_{n} = 3\mu_{p}$ ,

$$t_{PROP} = \frac{L_{\min}^2}{\mu_n (V_{DD} - V_T)} (W_1 + W_2) \left( \frac{1}{W_1} + \frac{3}{W_2} \right) = \frac{L_{\min}^2}{\mu_n (V_{DD} - V_T)} (4 + \frac{W_2}{W_1} + 3 \frac{W_1}{W_2})$$

Note speed is a function of device sizing!

Can device sizing be used to minimize t<sub>PROP</sub>?

For 
$$L_2 = L_1 = L_{\min}$$
,  $\mu_n = 3\mu_p$ ,
$$t_{PROP} = \frac{L_{\min}^2}{\mu_n (V_{DD} - V_T)} (4 + \frac{W_2}{W_1} + 3\frac{W_1}{W_2})$$

#### Can device sizing be used to minimize t<sub>PROP</sub>?

Assume W<sub>1</sub>=W<sub>MIN</sub>

$$\begin{split} \frac{\partial t_{\text{PROP}}}{\partial W_2} = & \left[ \frac{L_{\text{min}}^2}{\mu_n \left( V_{\text{DD}} - V_{\text{TH}} \right)} \right] \left[ \frac{1}{W_{\text{MIN}}} - 3 \frac{W_{\text{MIN}}}{W_2^2} \right] = 0 \\ \frac{1}{W_{\text{MIN}}} - 3 \frac{W_{\text{MIN}}}{W_2^2} = 0 \end{split}$$

$$W_{2} = \sqrt{3}W_{MIN}$$

$$t_{PROP} = \frac{L_{min}^{2}}{\mu_{n}(V_{DD} - V_{T})}(4 + 2\sqrt{3}) \cong \frac{L_{min}^{2}}{\mu_{n}(V_{DD} - V_{T})}(7.5)$$

$$t_{PROP} = t_{HL} + t_{LH} \cong C_L \left( R_{PU} + R_{PD} \right)$$
 If  $V_{Tn} = -V_{Tn} = V_T$  and  $C_L = C_{LN}$ 

#### For min size observe:

$$t_{PROP} = C_{OX}(W_{1}L_{1} + W_{2}L_{2}) \left( \frac{L_{1}}{\mu_{n}C_{OX}W_{1}(V_{DD} - V_{T})} + \frac{L_{2}}{\mu_{p}C_{OX}W_{2}(V_{DD} - V_{T})} \right)$$

$$If L_{2} = L_{1} = L_{min}, W_{1} = W_{2} = W_{min}, \ \mu_{n} = 3\mu_{p},$$

$$t_{PROP} = \frac{L_{min}^{2}}{\mu_{n}(V_{DD} - V_{T})} (W_{1} + W_{2}) \left( \frac{1}{W_{1}} + \frac{3}{W_{2}} \right) = \frac{L_{min}^{2}}{\mu_{n}(V_{DD} - V_{T})} (2W_{min}) \left( \frac{1}{W_{min}} + \frac{3}{W_{min}} \right)$$

For min size:

$$W_{2}=W_{1}=W_{min}$$

$$t_{PROP}=\frac{8L_{min}^{2}}{\mu_{1}(V_{DD}-V_{T})}$$

$$t_{PROP} = t_{HL} + t_{LH} \cong C_L (R_{PU} + R_{PD})$$

If 
$$V_{Tn} = -V_{Tp} = V_T$$
 and  $C_L = C_{IN}$ 

For equal rise/fall (with  $W_1=W_{min}$ ):

$$t_{PROP} = C_{OX}(W_{1}L_{1} + W_{2}L_{2}) \left( \frac{L_{1}}{\mu_{n}C_{OX}W_{1}(V_{DD} - V_{T})} + \frac{L_{2}}{\mu_{p}C_{OX}W_{2}(V_{DD} - V_{T})} \right)$$

If 
$$L_2 = L_1 = L_{\min}$$
,  $W_1 = W_{\min}$ ,  $\mu_n = 3\mu_p$ ,

$$t_{PROP} = \frac{L_{min}^{2}}{\mu_{1}(V_{DP} - V_{1})} (W_{1} + W_{2}) \left( \frac{1}{W_{1}} + \frac{3}{W_{2}} \right) \qquad \qquad W_{2} = 3W_{1}$$

For equal rise/fall:

$$W_{2} = 3W_{1}$$

$$t_{PROP} = \frac{8L_{min}^{2}}{\mu_{n}(V_{DD} - V_{T})}$$

$$t_{PROP} = t_{HL} + t_{LH} \cong C_L (R_{PU} + R_{PD})$$

#### **Summary:**

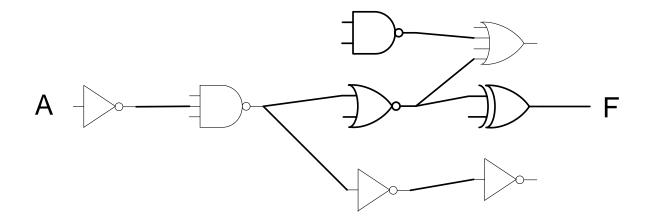
If 
$$V_{Tn} = -V_{Tp} = V_T$$
 and  $C_L = C_{IN}$  and  $L_2 = L_1 = L_{min}$ ,  $\mu_n = 3\mu_p$ ,

For min size: For equal rise/fall: For min delay: 
$$W_{2} = W_{1} = W_{min} \qquad W_{2} = 3W_{1} \qquad W_{2} = \sqrt{3}W_{1}$$

$$t_{PROP} = \frac{8L_{min}^{2}}{\mu_{n}(V_{DD} - V_{T})} \qquad t_{PROP} = \frac{8L_{min}^{2}}{\mu_{n}(V_{DD} - V_{T})} \qquad t_{PROP} = \frac{(4 + 2\sqrt{3})L_{min}^{2}}{\mu_{n}(V_{DD} - V_{T})} \qquad (4 + 2\sqrt{3}) \cong 7.5$$

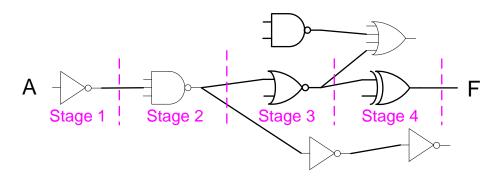
- Propagation Delay About the Same for 3 Sizing Strategies
- And for these sizing strategies all are near that of minimum delay!
- Have now introduced 4 device sizing strategies (3 based upon propagation delay and one to set V<sub>TRIP</sub>=V<sub>DD</sub>/2)

Will return to the issue of device sizing later



The propagation delay through k levels of logic is approximately the sum of the individual propagation delays in the same path

#### **Example:**



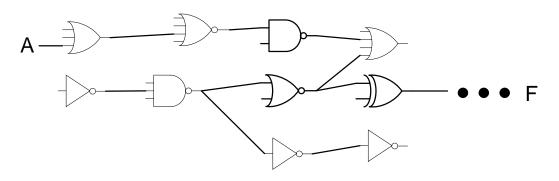
$$t_{\text{HL}} = t_{\text{HL4}} + t_{\text{LH3}} + t_{\text{HL2}} + t_{\text{LH1}}$$

$$t_{LH}=t_{LH4}+t_{HL3}+t_{LH2}+t_{HL1}$$

$$t_{PROP} = t_{LH} + t_{HL} = (t_{LH4} + t_{HL3} + t_{LH2} + t_{HL1}) + (t_{HL4} + t_{LH3} + t_{HL2} + t_{LH1})$$

$$t_{PROP} = t_{LH} + t_{HL} = (t_{LH4} + t_{HL4}) + (t_{LH3} + t_{HL3}) + (t_{LH2} + t_{HL2}) + (t_{LH1} + t_{HL1})$$

$$t_{PROP} = t_{PROP4} + t_{PROP3} + t_{PROP2} + t_{PROP1}$$



#### Propagation through k levels of logic

$$t_{HL} \cong t_{HLk} + t_{LH(k-1)} + t_{HL(k-2)} + \cdots + t_{XY1}$$

$$t_{LH} \cong t_{LHk} + t_{HL(k-1)} + t_{LH(k-2)} + \cdots + t_{YX1}$$

where X=H and Y=L if k odd and X=L and Y=h if k even

$$t_{PROP} = \sum_{i=1}^{k} t_{PROPk}$$

Will return to propagation delay after we discuss device sizing in more detail



# Stay Safe and Stay Healthy!

# End of Lecture 39